TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor SCHS174B

February 1998 - Revised May 2003

Features

- Common Clock and Asynchronous Master Reset
- Positive Edge Triggering
- Buffered Inputs
- Fanout (Over Temperature Range)
 - Standard Outputs 10 LSTTL Loads
 - Bus Driver Outputs 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility, V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)
 - CMOS Input Compatibility, II \leq 1µA at VOL, VOH

CD54HC273, CD74HC273, CD54HCT273, CD74HCT273

High-Speed CMOS Logic Octal D-Type Flip-Flop with Reset

Description

The 'HC273 and 'HCT273 high speed octal D-Type flip-flops with a direct clear input are manufactured with silicon-gate CMOS technology. They possess the low power consumption of standard CMOS integrated circuits.

Information at the D inputis transferred to the Q outputs on the positive-going edge of the clock pulse. All eight flip-flops are controlled by a common clock (CP) and a common reset ($\overline{\text{MR}}$). Resetting is accomplished by a low voltage level independent of the clock. All eight Q outputs are reset to a logic 0.

Ordering Information

PART NUMBER	TEMP. RANGE (^o C)	PACKAGE
CD54HC273F3A	-55 to 125	20 Ld CERDIP
CD74HC273E	-55 to 125	20 Ld PDIP
CD74HC273M	-55 to 125	20 Ld SOIC
CD74HC273M96	-55 to 125	20 Ld SOIC
CD54HCT273F3A	-55 to 125	20 Ld CERDIP
CD74HCT273E	-55 to 125	20 Ld PDIP
CD74HCT273M	-55 to 125	20 Ld SOIC
CD74HCT273M96	-55 to 125	20 Ld SOIC

NOTE: When ordering, use the entire part number. The suffix 96 denotes tape and reel.

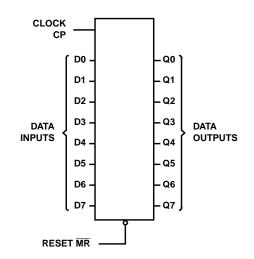
Pinout

		HC273, CD54 (CERDIP) HC273, CD74 (PDIP, SOIC TOP VIEW	HC	
			1	
MR	1		20	Vcc
QO	2		19	Q7
D0	3		18	D7
D1	4		17	D6
Q1	5		16	Q6
Q2	6		15	Q5
D2	7		14	D5
D3	8		13	D4
Q3	9		12	Q4
GND	10		11	СР

CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

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Functional Diagram



TRUTH TABLE

	INPUTS		OUTPUT
RESET (MR)	CLOCK CP	DATA D _n	Q
L	Х	Х	L
н	\uparrow	н	Н
н	\uparrow	L	L
Н	L	Х	Q ₀

H = High Voltage Level, L = Low Voltage Level, X = Don't Care, \uparrow = Transition from Low to High Level, Q₀ = Level Before the Indicated Steady-State Input Conditions Were Established.

Absolute Maximum Ratings

DC Supply Voltage, V _{CC}
For $V_1 < -0.5V$ or $V_1 > V_{CC} + 0.5V$ ±20mA
DC Output Diode Current, I _{OK}
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$
DC Drain Current, per Output, I _O
For -0.5V < V _O < V _{CC} + 0.5V±25mA
DC Output Source or Sink Current per Output Pin, IO
For $V_{O} > -0.5V$ or $V_{O} < V_{CC} + 0.5V$
DC V _{CC} or Ground Current, I _{CC} ±50mA

Operating Conditions

Temperature Range, T _A 55°C to 125°C
Supply Voltage Range, V _{CC}
HC Types2V to 6V
HCT Types
DC Input or Output Voltage, VI, VO 0V to VCC
Input Rise and Fall Time
2V
4.5V 500ns (Max)
6V

Thermal Information

Thermal Resistance (Typical, Note 1)	θ _{JC} (^o C/W)
E (PDIP) Package	69
M (SOIC) Package	58
Maximum Junction Temperature	150 ⁰ C
Maximum Storage Temperature Range65	^o C to 150 ^o C
Maximum Lead Temperature (Soldering 10s)	300 ⁰ C
(SOIC - Lead Tips Only)	

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. The package thermal impedance is calculated in accordance with JESD 51-7.

DC Electrical Specifications

			ST ITIONS			25 ⁰ C		-40 ⁰ C 1	O 85 ⁰ C	-55 ⁰ С Т	O 125 ⁰ C	
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES	-		-									
High Level Input	V _{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input	V _{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output	V _{OH}	V _{IH} or	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
Voltage CMOS Loads		VIL	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Voltage TTL Loads			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output	V _{OL}	V _{IH} or	0.02	2	-	-	0.1	-	0.1	-	0.1	V
Voltage CMOS Loads		VIL	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output	Output	4	4.5	-	-	0.26	-	0.33	-	0.4	V	
Voltage TTL Loads			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	lı	V _{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	μA
Quiescent Device Current	Icc	V _{CC} or GND	0	6	-	-	8	-	80	-	160	μA

		TEST CONDITIONS			25 ⁰ C			-40°C TO 85°C		-55°C TO 125°C		
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HCT TYPES												
High Level Input Voltage	VIH	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	lı	V _{CC} to GND	0	5.5	-	-	±0.1	-	±1	-	±1	μA
Quiescent Device Current	Icc	V _{CC} or GND	0	5.5	-	-	8	-	80	-	160	μA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI _{CC} (Note 2)	V _{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μA

NOTE:

2. For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
MR	1.5
Data	0.4
СР	1.5

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g., 360µA max at 25^oC.

Prerequisite For Switching Specifications

		TEST	TEST V _{CC}	25 ⁰ C		-40°C TO 85°C		-55°C TO 125°C			
PARAMETER	SYMBOL	CONDITIONS	(V)	MIN	ТҮР	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES	-				-		-	-	-	-	
Maximum Clock Frequency (Figure 1)	f _{MAX}	-	2	6	-	-	5	-	4	-	MHz
			4.5	30	-	-	25	-	20	-	MHz
			6	35	-	-	29	-	23	-	MHz
MR Pulse Width	t _W	-	2	60	-	-	75	-	90	-	ns
(Figure 1)			4.5	12	-	-	15	-	18	-	ns
			6	10	-	-	13	-	15	-	ns

		TEST	v _{cc}		25°C	;	-40 ⁰ C 1	O 85°C	-55 ⁰ С Т	O 125 ⁰ C	
PARAMETER	SYMBOL	-	s (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Clock Pulse Width (Figure 1)	t _W	-	2	80	-	-	100	-	120	-	ns
			4.5	16	-	-	20	-	24	-	ns
			6	14	-	-	17	-	20	-	ns
Set-up Time Data to Clock	ts∪	-	2	60	-	-	75	-	70	-	ns
(Figure 5)			4.5	12	-	-	15	-	18	-	ns
			6	10	-	-	13	-	15	-	ns
Hold Time, Data to Clock	tH	-	2	3	-	-	3	-	3	-	ns
(Figure 5)			4.5	3	-	-	3	-	3	-	ns
			6	3	-	-	3	-	3	-	ns
Removal Time, MR to Clock	t _{REM}	-	2	50	-	-	65	-	75	-	ns
			4.5	10	-	-	13	-	15	-	ns
			6	9	-	-	11	-	13	-	ns
HCT TYPES	-										
Maximum Clock Frequency (Figure 2)	f _{MAX}	-	4.5	25	-	-	20	-	16	-	MHz
MR Pulse Width (Figure 2)	t _w	-	4.5	12	-	-	15	-	18	-	ns
Clock Pulse Width (Figure 2)	t _w	-	4.5	20	-	-	25	-	30	-	ns
Set-up Time Data to Clock (Figure 6)	ts∪	-	4.5	12	-	-	15	-	18	-	ns
Hold Time, Data to Clock (Figure 6)	tH	-	4.5	3	-	-	3	-	3	-	ns
Removal Time, MR to Clock	t _{REM}	-	4.5	10	-	-	13	-	15	-	ns
Switching Specification	15 Input tr. tr	6ns									
									-55°	сто	
		TEST			25 ⁰	С	-40°C	ГО 85 ⁰ С	125		
PARAMETER	SYMBOL	CONDITIONS	V _{CC} (V)) Т	YP	MAX	м	AX	м	۹X	UNITS
HC TYPES											
Propagation Delay,	t _{PLH} , t _{PHL}	C _L = 50pF	2		-	150	1	90	22	25	ns
Clock to Output (Figure 3)			4.5		-	30	;	38	4	5	ns
			6		-	26	:	30	3	8	ns
	ľ	C _L = 15pF	5	1	2	-		-		-	ns
Propagation Delay,	t _{PHL}	C _L = 50pF	2		-	150	1	90	22	25	ns
MR to Output (Figure 3)			4.5		-	30	;	38	4	5	ns
× • • • /			6		-	26	:	30	3	8	ns
Output Transition Time	t _{TLH} , t _{THL}	C _L = 50pF	2		-	75	9	95	1'	10	ns
(Figure 3)			4.5		-	15	· ·	19	2	2	ns
			-	_		-					-

6

-

5

-

 $C_L = 15 pF$

Input Capacitance

Maximum Clock Frequency

CI

 $\mathsf{f}_{\mathsf{MAX}}$

13

10

-

-

-

60

16

10

-

19

10

-

ns

pF

MHz

		TEST	V _{CC} (V)	25	°C	-40°C TO 85°C	-55 ⁰ C TO 125 ⁰ C	
PARAMETER	SYMBOL	CONDITIONS		TYP	МАХ	MAX	MAX	
Power Dissipation Capacitance (Notes 3, 4)	C _{PD}	-	5	25	-	-	-	pF
HCT TYPES						-		•
Propagation Delay, t _P Clock to Output (Figure 4)	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	30	38	45	ns
		C _L = 15pF	5	12	-	-	-	ns
Propagation Delay, $\overline{\text{MR}}$ to Output (Figure 4)	^t PHL	C _L = 50pF	4.5	-	32	40	48	ns
Output Transition Time	t _{TLH} , t _{THL}	C _L = 50pF	4.5	-	15	19	22	ns
Input Capacitance	C _{IN}	-	-	-	10	10	10	pF
Maximum Clock Frequency	f _{MAX}	C _L = 15pF	5	50	-	-	-	MHz
Power Dissipation Capacitance (Notes 3, 4)	C _{PD}	-	5	25	-	-	-	pF

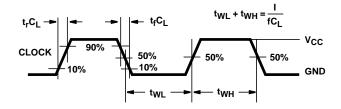
Switching Specifications Input t_r , $t_f = 6ns$ (Continued)

NOTES:

3. $C_{\mbox{PD}}$ is used to determine the dynamic power consumption, per flip-flop.

4. $P_D = C_{PD} V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 + f_0)$ where $f_i =$ Input Frequency, $f_O =$ Output Frequency, $C_L =$ Output Load Capacitance, $V_{CC} =$ Supply Voltage.

Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX} , input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

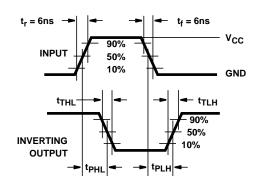
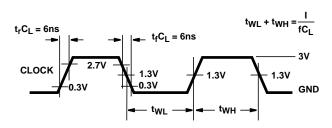
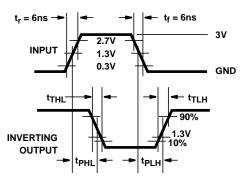


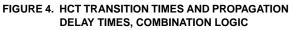
FIGURE 3. HC AND HCU TRANSITION TIMES AND PROPAGA-TION DELAY TIMES, COMBINATION LOGIC

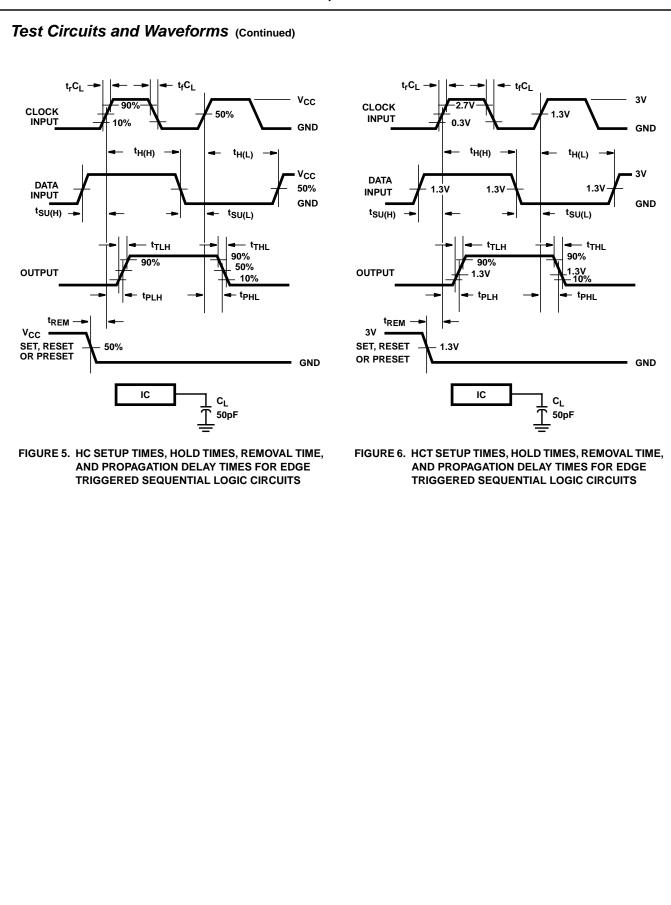


NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX} , input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH









25-Sep-2013

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8772501RA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8772501RA CD54HCT273F3A	Samples
CD54HC273F	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HC273F	Samples
CD54HC273F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	8409901RA CD54HC273F3A	Samples
CD54HCT273F	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HCT273F	Samples
CD54HCT273F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8772501RA CD54HCT273F3A	Samples
CD74HC273E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC273E	Samples
CD74HC273EE4	ACTIVE	PDIP	Ν	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC273E	Samples
CD74HC273M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HC273M96	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HC273M96E4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HC273M96G4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HC273ME4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HC273MG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC273M	Samples
CD74HCT273E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT273E	Samples
CD74HCT273EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT273E	Samples
CD74HCT273M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples
CD74HCT273M96	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples



25-Sep-2013

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD74HCT273M96E4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples
CD74HCT273M96G4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples
CD74HCT273ME4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples
CD74HCT273MG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT273M	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



25-Sep-2013

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD54HC273, CD54HCT273, CD74HC273, CD74HCT273 :

- Catalog: CD74HC273, CD74HCT273
- Military: CD54HC273, CD54HCT273

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com

TAPE AND REEL INFORMATION

REEL DIMENSIONS

Texas Instruments





TAPE AND REEL INFORMATION

TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC273M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CD74HCT273M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1

TEXAS INSTRUMENTS

www.ti.com

PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC273M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HCT273M96	SOIC	DW	20	2000	367.0	367.0	45.0

J (R-GDIP-T**) 14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- \triangle The 20 pin end lead shoulder width is a vendor option, either half or full width.



DW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AC.



LAND PATTERN DATA



NOTES:

A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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